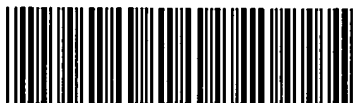


Search Notes

Application/Control No.

10/606,138

Examiner

James K. Trujillo

Applicant(s)/Patent under
Reexamination

AYYAVU ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner
713	300,320, 322,323, 324	12/8/2004	JKT
updated		5/9/2005	JKT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Databases: EAST NPL: IEEE, ACM	12/8/2004	JKT
updated	5/9/2005	JKT